
Proceedings of the Ninth Annual Symposium in Scanning Electron Microscopy are published in two volumes. The present review is concerned with the first of these, covering the symposium proper and workshops on physical applications of the scanning electron microscope and micro-electronic device fabrication and quality control with the electron microscope. Finally, several tutorial papers are included, and an additional bibliography on cathodoluminescence and a similar collection of information relevant to forensic applications of SEM is included. All of these are welcomed.

Reference to microscopy conjures in the minds of many a merely qualitative, even pictorial techniques of electron microscopy, for example, X-ray, cathodoluminescence, Auger, etc., strongly represented in this volume, must dispel such a misconception about the now well-established status of scanning electron microscopy.

The opening papers testify to the still unresolved controversy about the exact nature of the interaction of electrons in the surface of solid matter and, in particular, the origin of contrast in SEM images.

The 'take-over' of scanning transmission electron microscopy (STEM) under the umbrella of the symposium must be considered as a valuable acquisition. As usual, papers from Cowley's laboratory form the highlight of these proceedings. He shows how electron diffraction information can be used to derive the position of atoms within large biological molecules, adding that the 'phase problem', familiar in X-ray diffraction, may be overcome in several ways. Moreover, Cowley correctly argues that such a method is capable of reducing electron damage below that involved when images of the atoms are sought directly, either by bright or dark-field techniques. One hopes that practical realization of this will provide a useful complementary adjunct to other methods of great importance in the study of crystalline and paracrystalline solids; the method has obvious advantages over labelling with heavier atoms, also represented in the symposium.

A few years after the inception of what, until now, one recognized as the Chicago Annual Symposia, views were heard that it might not be possible to sustain the enthusiasm felt at the beginning (in 1968), when the band of workers eagerly followed the pioneering investigators of the Cambridge school. Of course, the expansion in new directions and the numerical growth of users must be regarded as significant when one considers the scientific success of these symposia and the associated activities. Yet all involved, over a period of nearly ten years, in the work of these symposia will doubtless agree with this reviewer that without the faith and vision of the man who conceived the idea of an international gathering of this kind, the impetus would have waned. Dr Johari has been able to give us an example of what can be achieved by the widest possible consultations, calling on referees from all corners of the world (there are some 200 names given in the present volume) and by careful editing of the text, including the comments of its referees with each paper.

The question arises whether a volume listing 116 positions in the subject index, can represent uniform scientific standards. Clearly, 'tutorial' contributions inevitably lead to the inclusion of somewhat dated information. Moreover, looking carefully over the exchanges between the authors and the referees, one feels that the editor becomes too much involved, so that the original (not necessarily incorrect) ideas give way to the convictions of a selected few.

On the whole, the phenomena at the surface of solids due to the action of electrons are well covered: for example, progress in the understanding of electrostatic charging; temperature measurements in samples inside the electron microscope (using thin-film thermocouples); environmental cells (for the examination of water-containing specimens); advantages and disadvantages of low-temperature cells for biological specimens; the problems of fabrication of micro-electronic devices and quality control – two enormous areas, well covered in the proceedings.

This reviewer, on this side of the Atlantic, found some of the recognized (?) terminology and, in particular, some of the abbreviations a little unnerving. However, the present volume will join publications from the previous symposia, as a standard reference in any laboratory engaged in the art of scanning electron microscopy.

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In spite of the unassuming title, this is a rather good textbook of contemporary solid-state physics aimed at the good undergraduate, the postgraduate and the lecturer. The text consists of 12 chapters and 516 pages with narrow margins resulting in a very high ratio of text area to page area – ½ compared with a norm usually below ⅓. The book is packed with information which is very up-to-date: as a quarry of appropriate examples, interesting exercises, references, beautifully-drawn diagrams and topical discussion it is a lecturer's dream. The topics covered are crystal lattices (perhaps the most rapid resumé I have ever seen), diffraction, interatomic forces, lattice vibrations, band theory, electronic properties of solids with and without a magnetic field, semiconductors and superconductors, mag-